

SILICON TRANSISTOR 2SC3583

MICROWAVE LOW NOISE AMPLIFIER NPN SILICON EPITAXIAL TRANSISTOR

DESCRIPTION

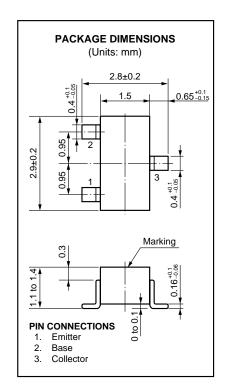
The 2SC3583 is an NPN epitaxial silicon transistor designed for use in low-noise and small signal amplifiers from VHF band to UHF band. Low-noise figure, high gain, and high current capability achieve a very wide dynamic range and excellent linearity. This is achieved by direct nitride passivated base surface process (DNP process) which is an NEC proprietary new fabrication technique.

FEATURES

NF 1.2 dB TYP. @f = 1.0 GHz
Ga 13 dB TYP. @f = 1.0 GHz

ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

Collector to Base Voltage	Vсво	20	V
Collector to Emitter Voltage	VCEO	10	V
Emitter to Base Voltage	Vево	1.5	V
Collector Current	Ic	65	mΑ
Total Power Dissipation	Рт	200	mW
Junction Temperature	Tj	150	°C
Storage Temperature	Tstg	-65 to +150	°C



ELECTRICAL CHARACTERISTICS (TA = 25 °C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Collector Cutoff Current	Ісво			1.0	μА	Vcb = 10 V, IE = 0
Emitter Cutoff Current	ІЕВО			1.0	μА	VEB = 1 V, IE = 0
DC Current Gain	hfe*	50	100	250		Vce = 8 V, Ic = 20 mA
Gain Bandwidth Product	f⊤		9		GHz	Vce = 8 V, Ic = 20 mA
Feed-Back Capacitance	Cre **		0.35	0.9	pF	Vcb = 10 V, IE = 0, f = 1.0 MHz
Insertion Power Gain	S _{21e} 2	11	13		dB	Vce = 8 V, Ic = 20 mA, f = 1.0 GHz
Maximum Available Gain	MAG		15		dB	Vce = 8 V, Ic = 20 mA, f = 1.0 GHz
Noise Figure	NF		1.2	2.5	dB	Vce = 8 V, Ie = 7 mA, f = 1.0 GHz

^{*} Pulse Measurement PW ≤ 350 μs, Duty Cycle ≤ 2 %

hfe Classification

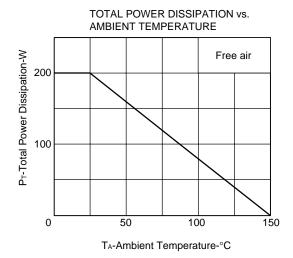
Class	R33/Q *	R34/R *	R35/S *				
Marking	R33	R34	R35				
hfe	50 to 100	80 to 160	125 to 250				

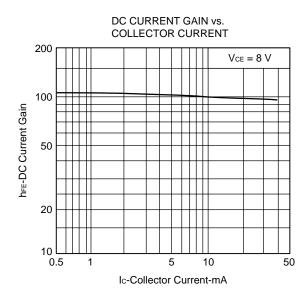
^{*} Old Specification / New Specification

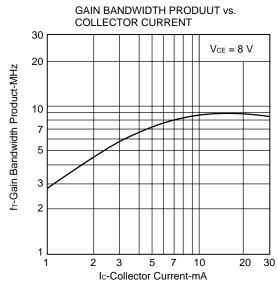
^{**} The emitter terminal and the case shall be connected to the gurad terminal of the three-terminal capacitance bridge.

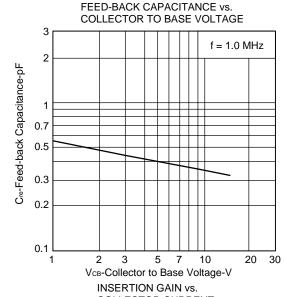


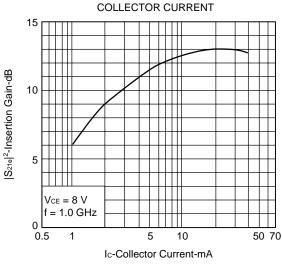
TYPICAL CHARACTERISTICS (TA = 25 °C)

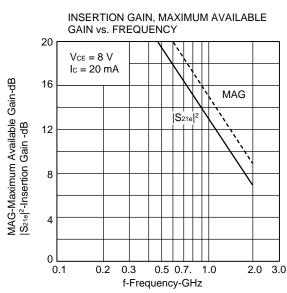


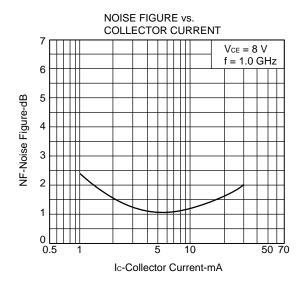












S-PARAMETER

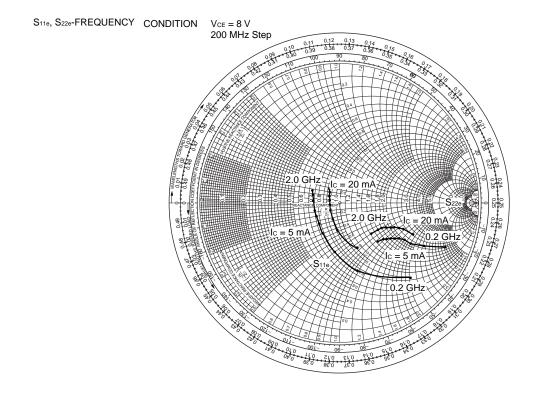
 $V_{CE} = 8.0 \text{ V}$, $I_{C} = 5.0 \text{ mA}$, $Z_{O} = 50 \Omega$

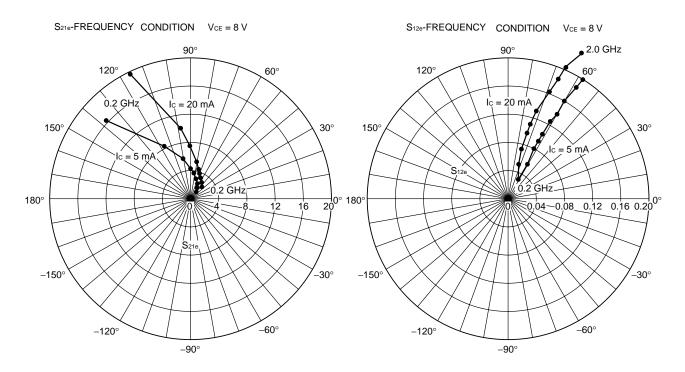
VCE - 0.0 \	v, ic = 3.0 iii.	A, 20 – 30 sz						
f (MHz)	S ₁₁	∠ S ₁₁	S ₂₁	∠ S 21	S ₁₂	∠ S ₁₂	S ₂₂	∠ S 22
200	0.728	-45.3	12.107	138.7	0.036	66.2	0.825	-21.6
400	0.490	-74.5	8.097	114.2	0.065	61.6	0.675	-26.6
600	0.343	-93.2	6.260	102.3	0.079	61.6	0.582	-29.0
800	0.253	-110.1	4.623	90.1	0.090	61.2	0.529	-28.6
1000	0.202	-131.1	4.004	83.6	0.101	61.3	0.500	-30.1
1200	0.176	-148.9	3.250	75.8	0.125	60.8	0.470	-31.4
1400	0.176	-162.8	3.021	69.4	0.144	60.0	0.448	-33.4
1600	0.179	173.9	2.575	63.4	0.160	59.8	0.427	-34.8
1800	0.186	163.3	2.520	58.9	0.188	59.1	0.406	-37.5
2000	0.211	151.1	2.183	53.4	0.202	58.9	0.386	-44.5
Vce = 8.0 \	/, Ic = 20 m/	A , $Zo = 50 \Omega$						
f (MHz)	S ₁₁	∠ S ₁₁	S ₂₁	∠ S 21	S ₁₂	∠ S ₁₂	S22	∠ S 22
200	0.366	-66.8	19.757	116.9	0.033	62.6	0.587	-22.5

f (MHz)	S ₁₁	∠ S ₁₁	S ₂₁	∠ S 21	S ₁₂	∠ S ₁₂	S ₂₂	∠ S22
200	0.366	-66.8	19.757	116.9	0.033	62.6	0.587	-22.5
400	0.194	-88.9	10.502	98.8	0.055	70.6	0.485	-23.8
600	0.124	-104.3	7.591	91.1	0.072	74.6	0.453	-24.3
800	0.077	-132.0	5.446	82.0	0.095	73.2	0.419	-23.2
1000	0.063	-156.4	4.653	77.6	0.107	72.1	0.413	-24.2
1200	0.065	179.5	3.754	71.6	0.135	72.1	0.392	-26.4
1400	0.074	168.0	3.460	66.5	0.164	70.1	0.369	-29.9
1600	0.108	147.0	2.934	61.9	0.178	69.6	0.347	-32.2
1800	0.116	137.6	2.870	58.2	0.205	66.3	0.333	-34.3
2000	0.134	131.2	2.479	53.4	0.221	64.0	0.312	-42.1

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S-PARAMETER





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Anti-radioactive design is not implemented in this product.

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